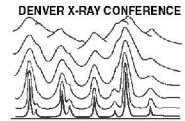


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[Table of
Contents](#)

[View
Document](#)

CONTENTS

I. SURFACE AND NEAR-SURFACE X-RAY SPECTROSCOPY

RECENT DEVELOPMENTS AND RESULTS IN TOTAL REFLECTION X-RAY FLUORESCENCE ANALYSIS	1
P. Wobrauschek, P. Kregsamer, C. Strelt and H. Aiginger	
GLANCING ANGLE X-RAY ABSORPTION SPECTROSCOPY	13
G. N. Greaves	
SEMICONDUCTOR SURFACE CHARACTERIZATION BY SYNCHROTRON X-RAY FLUORESCENCE ANALYSIS	23
A. Iida	
TOTAL-REFLECTION X-RAY FLUORESCENCE OF THIN LAYERS ON AND IN SOLIDS.	35
D. K. G. de Boer and W. W. van den Hoogenhof	

II. DETERMINATION OF LOW CONCENTRATION LEVELS
BY X-RAY SPECTROMETRY

TRACE ELEMENT ANALYSIS OF SOLUTIONS AT THE PPB LEVEL	41
C. Meltzer and B-S. King	
TRACE ANALYSIS USING EDS: APPLICATIONS TO THIN-FILM AND HETEROGENEOUS SAMPLES	57
B. J. Cross and J. E. Augenstine	
GRAZING INCIDENCE X-RAY FLUORESCENCE ANALYSIS WITH MONOCHROMATIC RADIATION	71
M. Schuster	
IMPURITY ANALYSIS ON Si WAFER USING MONOCHRO-TREX	81
K. Nishihagi, N. Yamashita, N. Fujino, K. Taniguchi and S. Ikeda	

III. LONG-WAVELENGTH X-RAY SPECTROMETRY

CHEMICAL STATE ANALYSIS BY SOFT X-RAY EMISSION SPECTRA WITH MOLECULAR-ORBITAL CALCULATIONS	91
J. Kawai	

FUNDAMENTALS OF X-RAY SPECTROMETRIC ANALYSIS USING LOW-ENERGY ELECTRON EXCITATION	105
M. J. Romand, F. Gaillard, M. Charbonnier and D. S. Urch	
CHEMICAL BONDING STUDIES OF SOLUTIONS BY HIGH RESOLUTION X-RAY FLUORESCENCE SPECTROSCOPY	123
T. Scimeca, S. Fukushima, K. Miyamura and Y. Gohshi	
ADVANCES IN BORON MEASUREMENT WITH WAVELENGTH DISPERSIVE XRF	131
B. W. Adamson, K. Juchli and G. Matula	
SOFT AND ULTRA-SOFT X-RAY SPECTROMETRY USING LONG-WAVELENGTH DISPERSIVE DEVICES	139
M. Charbonnier, F. Gaillard, M. J. Romand and D. S. Urch	
IV. XRF DATA REDUCTION	
REQUIREMENT ANALYSIS AND PRELIMINARY DESIGN FOR ENERGY DISPERSIVE X-RAY FLUORESCENCE ANALYSIS SOFTWARE	149
Z. Liu	
QUANTITATIVE XRF ANALYSIS USING THE FUNDAMENTAL ALGORITHM	157
R. M. Rousseau	
PRACTICAL APPLICATION FOR THE USE OF STATISTICS TO ESTABLISH QUALITY CONTROL AND IMPLEMENT QUALITY ASSURANCE IN X-RAY FLUORESCENCE	163
P. A. Ruggiero	
V. XRF INSTRUMENTATION AND TECHNIQUES	
DRIFT IN ENERGY CALIBRATION OF ENERGY DISPERSIVE X-RAY FLUORESCENCE ANALYZERS AND ITS CORRECTION	169
Z. Liu	
CURRENT AND FUTURE ENERGY DISPERSIVE EXAFS DETECTOR SYSTEMS	177
G. E. Derbyshire, W. I. Helsby, A. J. Dent, S. A. Wright, R. C. Farrow, G. N. Greaves, C. Morrell and G. J. Baker	
HIGH THROUGHPUT RATE SOLID STATE DETECTOR SYSTEMS FOR FLUORESCENCE EXAFS	187
G. E. Derbyshire, R. C. Farrow, R. L. Bilsborrow, C. Morrell, G. N. Greaves and B. R. Dobson	
A REVIEW OF THE RELATIVE MERITS OF LOW POWERED WDXRF AND EDXRF SPECTROMETERS FOR ROUTINE QUANTITATIVE ANALYSIS	193
B. J. Price, J. Padur and N. S. Robson	
IMAGING XPS. A CONTRIBUTION TO 3D X-RAY ANALYSIS	201
M. F. Ebel, H. Ebel, M. Mantler and R. Svagera	

GRAPHITE FUSION OF GEOLOGICAL SAMPLES	213
G. Luedemann, D. Mann and R. Hagan	
FAST, HIGH-RESOLUTION X-RAY MICROFLUORESCENCE IMAGING	217
D. A. Carpenter and M. A. Taylor	
HIGH-TEMPERATURE DISPLACEMENT MEASUREMENT USING A SCANNING FOCUSSED X-RAY LINE SOURCE	223
E. H. Jordan, H. A. Canistraro, D. M. Pease and D. Brewster	
ON-BELT DETERMINATION OF CALCIUM CONCENTRATION BY X-RAY FLUORESCENCE	231
M. Hirvonen	
NIObIUM CONCENTRATION MEASUREMENT IN STEEL SAMPLES WITH TXRF	239
F. Hegedüs and P. Winkler	
 VI. GEOLOGICAL AND OTHER APPLICATIONS OF X-RAY SPECTROMETRY 	
MASS ABSORPTION COEFFICIENT DETERMINATION USING COMPTON SCATTERED TUBE RADIATION: APPLICATIONS, LIMITATIONS AND PITFALLS	243
J. P. Willis	
TRACE ELEMENT ANALYSIS OF ROCKS BY X-RAY SPECTROMETRY	263
B. W. Chappell	
X-RAY FLUORESCENCE AND FIRE-ASSAY COLLECTION: USEFUL PARTNERS IN THE DETERMINATION OF THE PLATINUM-GROUP ELEMENTS	277
B. T. Eddy, B. L. Stuckenberg and G. Pansi	
X-RAY FLUORESCENCE ANALYSIS OF HIGH-DENSITY BRINES USING A COMPTON SCATTERING RATIO TECHNIQUE	285
M. L. Samuelson and S. B. McConnell	
SECONDARY TARGET X-RAY EXCITATION IN VIVO MEASUREMENT OF LEAD IN BONE	293
P. A. Pella and C. G. Soares	
PHOSPHORUS DETERMINATION IN BOROPHOSPHOSILICATE OR PHOSPHOSILICATE GLASS FILMS ON A SI WAFER BY WAVELENGTH DISPERSIVE X-RAY SPECTROSCOPY	299
H. S. Levine and K. L. Higgins	
NON-DESTRUCTIVE ANALYSIS OF VENEZUELAN ARTIFACTS OF DIFFERENT SIZES AND SHAPES FOR PROVENANCE STUDIES	307
J. J. LaBrecque, P. A. Rosales and O. Carias	
X-RAY FLUORESCENCE AS A PROBLEM-SOLVING TOOL IN THE PAPER INDUSTRY	313
W. K. Istone, J. M. Collier and J. A. Kaplan	

VII. SOLID STATE AND POSITION-SENSITIVE
DETECTORS FOR XRD

X-RAY DETECTORS: PULSE HEIGHT SHIFTS, ESCAPE PEAKS AND COUNTING LOSSES	319
M. A. Short	
MEASUREMENT OF MASS ABSORPTION COEFFICIENTS USING COMPTON-SCATTERED Cu RADIATION IN X-RAY DIFFRACTION ANALYSIS	325
S. J. Chipera and D. L. Bish	
EVALUATION OF THE X-RAY RESPONSE OF A POSITION-SENSITIVE MICROSTRIP DETECTOR WITH AN INTEGRATED READOUT CHIP	337
C. Rossington, J. Jaklevic, J. Reid, C. Haber and H. Spieler	
PRACTICAL AND "UNUSUAL" APPLICATIONS IN X-RAY DIFFRACTION USING POSITION SENSITIVE DETECTORS	349
R. G. Tissot and M. O. Eatough	
CCD BASED X-RAY DETECTORS	357
M. W. Tate	
WIDE ANGLE AND SMALL ANGLE X-RAY SCATTERING APPLICATIONS USING A TWO-DIMENSIONAL AREA DETECTOR	363
B. G. Landes, R. A. Newman and P. R. Rudolf	

VIII. QUALITATIVE AND QUANTITATIVE
PHASE ANALYSIS BY XRD

EVALUATION OF REFERENCE X-RAY DIFFRACTION PATTERNS IN THE ICDD POWDER DIFFRACTION FILE	369
G. J. McCarthy, J. M. Holzer, W. M. Syvinski, K. J. Martin and R. G. Garvey	
MATCHDB - A PROGRAM FOR THE IDENTIFICATION OF PHASES USING A DIGITIZED DIFFRACTION-PATTERN DATABASE	377
D. K. Smith, G. G. Johnson, Jr., and S. Q. Hoyle	
X-RAY DIFFRACTION ANALYSIS OF FLY ASH. II. RESULTS	387
G. J. McCarthy and J. K. Solem	
DEVELOPMENT OF A CALIBRATION METHOD FOR QUANTITATIVE X-RAY POWDER DIFFRACTION OF SIZE-SEGREGATED AEROSOLS	395
R. D. Giaque, J. M. Jaklevic and L. E. Sindelar	
STRATEGIES FOR PREFERRED ORIENTATION CORRECTIONS IN X-RAY POWDER DIFFRACTION USING LINE INTENSITY RATIOS	409
B. H. O'Connor, D. Y. Li and H. Sitepu	
QUANTIFICATION OF CARBAMAZEPINE IN TABLETS BY POWDER X-RAY DIFFRACTOMETRY	417
R. Suryanarayanan	

MASS ABSORPTION CORRECTED X-RAY DIFFRACTION ANALYSIS OF ENTRAINED-FLOW REACTOR COAL COMBUSTION PRODUCTS	429
L. W. Collins and D. L. Wertz	

IX. NONAMBIENT APPLICATION OF DIFFRACTION

A FOCUSING SYSTEM FOR X-RAY DIFFRACTION STUDIES OF MATERIALS UNDER HIGH PRESSURE IN THE DIAMOND CELL	437
Y. Wu, A. C. Thompson, J. H. Underwood, H. K. Mao, Y. W. Fei, J. Z. Hu, J. V. Badding and J. F. Shu	
PHASE ANALYSIS OF METALLIC PLUTONIUM-CONTAINING FUEL ALLOYS USING NEUTRON DIFFRACTION	447
M. H. Mueller, J. W. Richardson, Jr., R. V. Strain and G. L. Hofman	
HIGH-TEMPERATURE XRD ANALYSIS OF POLYMERS	459
R. W. Green	
RESIDUAL STRAINS IN Al_2O_3 / SiC (WHISKER) COMPOSITE FROM 25-1000°C	465
B. Ballard, P. K. Predecki and C. Hubbard	

X. CRYSTALLITE SIZE/STRAIN ANALYSIS

APPLICATIONS OF X-RAY DIFFRACTION CRYSTALLITE SIZE/STRAIN ANALYSIS TO SEISMOSAURUS DINOSAUR BONE	473
S. J. Chipera and D. L. Bish	
THE SUBSTRUCTURE OF AUSTENITE AND MARTENSITE THROUGH A CARBURIZED SURFACE	483
J. D. Makinson, W. N. Weins and R. J. De Angelis	
DETERMINATION OF LATTICE PARAMETER AND STRAIN OF γ' PHASES IN NICKEL-BASE SUPERALLOYS BY SYNCHROTRON RADIATION PARALLEL BEAM DIFFRACTOMETRY	493
K. Ohno, K. Ohsumi, H. Harada, T. Yamagata and M. Yamazaki	
THE EFFECT OF SATELLITE LINES FROM THE X-RAY SOURCE ON X-RAY DIFFRACTION PEAKS	501
F. E. Briden and D. F. Natschke	
X-RAY TOPOGRAPHY AND TEM STUDY OF CRYSTAL DEFECT PROPAGATION IN EPITAXIALLY GROWN AlGaAs LAYERS ON GaAs(001)	507
I. C. Bassignana, D. A. Macquistan and D. A. Clark	
LINESHAPE ANALYSIS OF X-RAY DIFFRACTION PROFILES: POLYETHYLENE AND MODEL COPOLYMERS	519
B. Crist and P. R. Howard	

**XI. THIN FILM AND SEMICONDUCTOR CHARACTERIZATION
BY X-RAY DIFFRACTION**

- DOUBLE-CRYSTAL X-RAY DIFFRACTION STUDIES OF Si ION-IMPLANTED AND
PULSED LASER-ANNEALED GaAs 531
P. M. Adams, J. F. Knudsen and R. C. Bowman, Jr.
- X-RAY CHARACTERIZATION OF THIN DIAMOND FILMS DEPOSITED BY
HOT-FILAMENT CHEMICAL VAPOR DEPOSITION 543
R. F. Hamilton, D. Garg, K. A. Wood and D. S. Hoover
- SUBSTRUCTURE-MAGNETIC PROPERTY CORRELATION IN Fe/Ag COMPOSITE
THIN FILMS 557
C. P. Reed, R. J. DeAngelis, Y. X. Zhang, S. H. Liou
and R. J. Jacob
- THE THICKNESS MEASUREMENTS OF THIN BULK FILM BY X-RAY METHOD 567
Y. Hirose, N. Takano, Y. Nanayama and T. Mura
- OXYGEN CONCENTRATION DETERMINATION IN SILICON SINGLE CRYSTALS
BY PRECISION LATTICE PARAMETER MEASUREMENT 577
H. Ohmori, M. Tomita, N. Tsuchiya and Y. Matsushita

**XII. ANALYSIS OF STRESS AND FRACTURE
BY DIFFRACTION METHODS**

- THERMAL STRESS RELAXATION IN VAPOR DEPOSITED THIN FILMS 587
I. C. Noyan and C. C. Goldsmith
- AN EXPERT SYSTEM FOR THE VALIDATION AND INTERPRETATION OF X-RAY
RESIDUAL STRESS DATA 601
M. Tricard, R. W. Hendricks and M. Guillot
- RESIDUAL STRESSES IN RAILROAD CAR WHEELS 611
J. Jo, R. W. Hendricks, R. E. Swanson and R. V. Foutz
- MEASUREMENT OF RESIDUAL STRESSES BY X-RAY DIFFRACTION NEAR SIMULATED
HEAT AFFECTED ZONES IN AUSTENITIC STAINLESS STEELS 623
V. S. Iyer, R. W. Hendricks and S. A. David
- USE OF X-RAY DIFFRACTION USING GAUSSIAN CURVE METHOD FOR MEASURING
PLASTIC STRAIN OF STEELS 633
M. Kurita and K. Chiaki
- X-RAY ELASTIC CONSTANTS FOR β -SiC AND RESIDUAL STRESS ANISOTROPY
IN A HOT-PRESSED Al₂O₃/SiC (WHISKER) COMPOSITE 643
P. Predecki, A. Abuhasan and C. S. Barrett
- X-RAY STUDY ON FATIGUE FRACTURE SURFACES OF ALUMINUM ALLOY
REINFORCED WITH SILICON CARBIDE WHISKERS 651
K. Funaki, Y. Nanayama, Y. Ichimaru, Y. Hirose and K. Tanaka

CONTENTS

xxi

RESIDUAL STRESS ANALYSIS OF SILICON NITRIDE TO CARBON STEEL JOINT . . . 661
M. Kurita, T. Kano and T. Sato

RESIDUAL STRESSES IN UNIDIRECTIONAL Al_2O_3 FIBER/SILICATE GLASS
COMPOSITES BY X-RAY DIFFRACTION 669
L. Hehn and P. Predecki

X-RAY RESIDUAL STRESS MEASUREMENT OF GROUND SURFACE OF METAL-CERAMIC
COMPOSITE 679
Z. Yajima, Y. Hirose, Y. Kishi and K. Tanaka

DETERMINATION OF X-RAY ELASTIC CONSTANTS IN A Ti-14Al-21Nb ALLOY
AND A Ti-14Al-21Nb/SiC METAL MATRIX COMPOSITE 689
J. Jo, R. W. Hendricks, W. D. Brewer and K. M. Brown

A METHOD FOR X-RAY STRESS ANALYSIS OF THIN FILMS AND ITS APPLICATION
TO ZINC-NICKEL-ALLOY ELECTROPLATED STEEL 699
T. Sasaki, M. Kuramoto and Y. Yoshioka

FRACTURE ANALYSIS OF NODULAR CAST IRON BY X-RAY FRACTOGRAPHY 711
K. Matsui, Y. Hirose, A. Chadani and K. Tanaka

X-RAY FRACTOGRAPHIC STUDY ON ALUMINA AND ZIRCONIA CERAMICS 719
S. Tanaka, Y. Hirose and K. Tanaka

Author Index 729

Subject Index 733